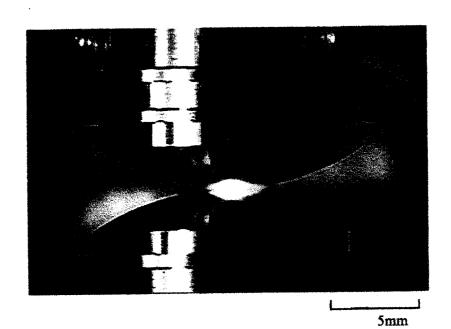
## Recent Experiments on Vacuum Breakdown of Oxygen-free Copper Electrodes

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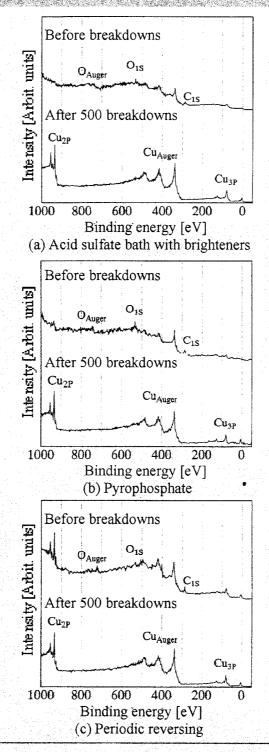
## Summary

- Low gas content copper, that is, vacuum-degassed Class 1 copper has a high hold-off voltage capability.
- To obtain a better breakdown strength, *in situ* surface cleaning is necessary.
- The annealing is effective in improving the breakdown strength.
- A mirror finish by the electrochemical buffing or diamond turning reduces the required number off breakdowns to achieve a higher breakdown field.
- The combination of annealing and diamond turning is effective to obtain a high breakdown field; the field reaches about 250 MV/m.
- The effect of diamond turning was discussed on the basis of the residual stresses on the electrode surfaces.

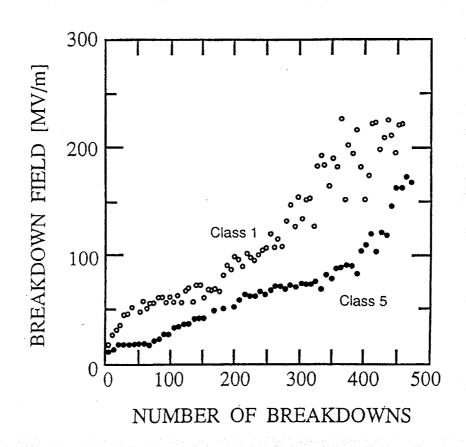


試料:無酸素銅

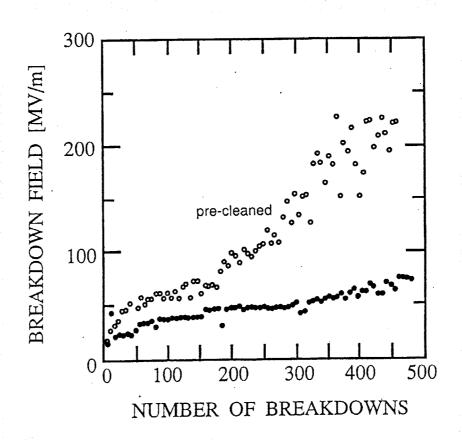
図3-5.絶縁破壊時の写真



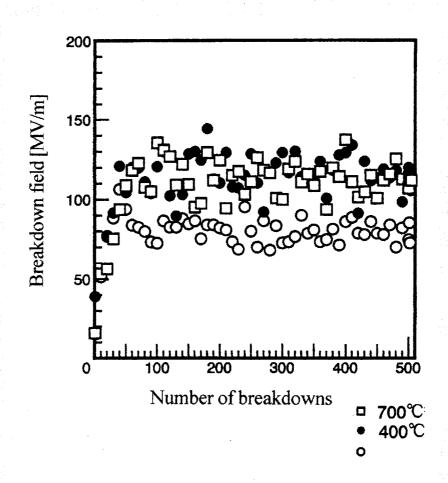
XPS spectra of electroformed copper



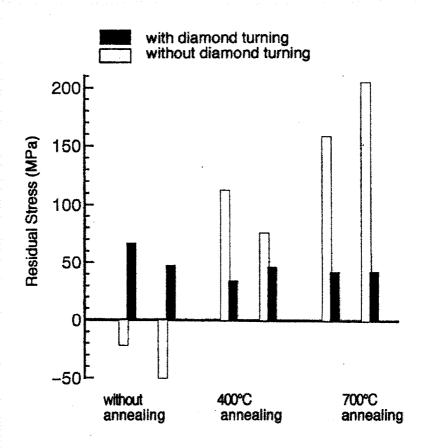
Difference of the breakdown fields between Class 1 and Class 5



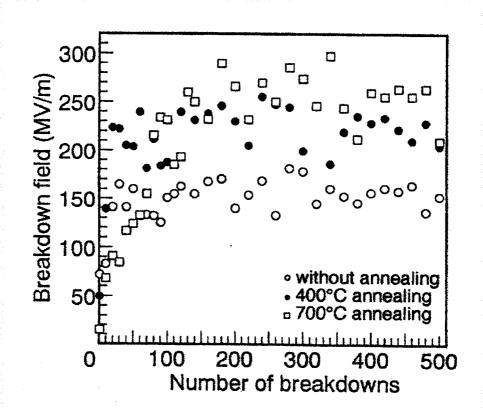
Effect of in situ pre-cleaning performed by Ar-ion sputtering on the breakdown fields. Class 1 copper was used.



Effect of annealing on the breakdown fields. The electrode surfaces were finished by ECB.



Residual surface stresses of OFC electrodes measured by X-ray diffraction method. Surface stresses after diamond turning show an almost constant value. Annealing was pretreated before diamond turning.

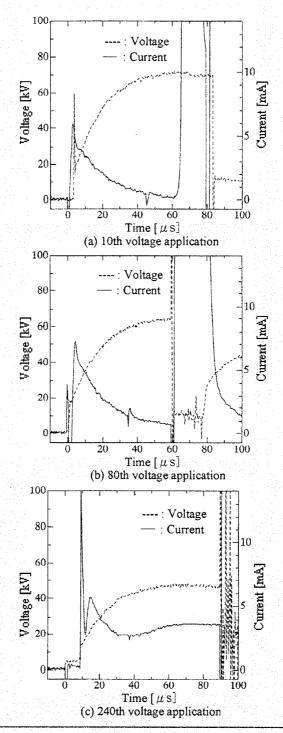


Effect of diamond turning and annealing on the breakdown field.

Table 3. First breakdown fields ( $E_1$ ) of electrofromed and other finished electrodes. DC impulse (64/700  $\mu$ s) testing.

copper	Ra	E <sub>1</sub>
electrode	(μm)	(MV/m)
turning		20
casted OFC  electrochemical buffing  (Class-1)  diamond turning	0.03	16
	0.06*	71
Periodic Reversing electroformed Acid sulfate (+ brightener)	0.40	41
	0.84	13
Pyrophosphate		10
	electrode  turning  electrochemical buffing  diamond turning  Periodic Reversing  Acid sulfate (+ brightener)	electrode (µm)  turning  electrochemical buffing 0.03  diamond turning 0.06*  Periodic Reversing 0.40  Acid sulfate (+ brightener) 0.84

<sup>\*</sup> Rmax



Voltage-current wave forms

- I V characteristics during DC impulse voltage conditioning
- a) initial stage; non-metallic layer or inclusion
  - \*current increase without volatge drop, followed by breakdown
  - \*hot electron emission through dielectric or oxide surface layer
- b) initial and/or intermediate stage; clump or microdust
  - \*current increases and voltage drops, simultaneously
  - \*removal and evaporation of clump, causing charged particles
- c) saturated and steady stage; metallic field emission
  - \*increase of field emission current, followed by breakdown
  - \*F-N type field emission from clean/metallic surface